


[Home](#) | [Login](#) | [Logout](#) | [Access Information](#) | [All](#)

Welcome United States Patent and Trademark Office

Search Results

[BROWSE](#)[SEARCH](#)[IEEE XPLORE GUIDE](#)

Results for "((current and leakage and scan and chain)<in>metadata)"

Your search matched 5 of 1416205 documents.

A maximum of 100 results are displayed, 25 to a page, sorted by Relevance in Descending order.

e-mail

» Search Options

[View Session History](#)[New Search](#)

Modify Search

((current and leakage and scan and chain)<in>metadata)

[Search](#) ☐ Check to search only within this results setDisplay Format: ☒ Citation ☐ Citation & Abstract

» Key

IEEE JNL IEEE Journal or Magazine

IEE JNL IEE Journal or Magazine

IEEE CNF IEEE Conference Proceeding

IEE CNF IEE Conference Proceeding

IEEE STD IEEE Standard

[view selected items](#) [Select All](#) [Deselect All](#)

- ☐ 1. Leakage current reduction in CMOS VLSI circuits by Input vector control
Abdollahi, A.; Fallah, F.; Pedram, M.;
[Very Large Scale Integration \(VLSI\) Systems. IEEE Transactions on](#)
Volume 12, Issue 2, Feb. 2004 Page(s):140 - 154
Digital Object Identifier 10.1109/TVLSI.2003.821546
[AbstractPlus](#) | [References](#) | Full Text: [PDF](#)(560 KB) IEEE JNL
[Rights and Permissions](#)
- ☐ 2. Leakage current reduction in sequential circuits by modifying the scan chains
Abdollahi, A.; Fallah, F.; Pedram, M.;
[Quality Electronic Design. 2003. Proceedings. Fourth International Symposium on](#)
24-26 March 2003 Page(s):49 - 54
Digital Object Identifier 10.1109/ISQED.2003.1194708
[AbstractPlus](#) | Full Text: [PDF](#)(243 KB) IEEE CNF
[Rights and Permissions](#)
- ☐ 3. A novel scan chain diagnostics technique based on light emission from leakage current
Song, P.; Stellari, F.; Xia, T.; Weger, A.J.;
[Test Conference. 2004. Proceedings. ITC 2004. International](#)
2004 Page(s):140 - 147
Digital Object Identifier 10.1109/TEST.2004.1386946
[AbstractPlus](#) | Full Text: [PDF](#)(830 KB) IEEE CNF
[Rights and Permissions](#)
- ☐ 4. A practical built-in current sensor for I_{DDQ} testing
Hoki Kim; Walker, D.M.H.; Colby, D.;
[Test Conference. 2001. Proceedings. International](#)
30 Oct.-1 Nov. 2001 Page(s):405 - 414
Digital Object Identifier 10.1109/TEST.2001.966657
[AbstractPlus](#) | Full Text: [PDF](#)(954 KB) IEEE CNF
[Rights and Permissions](#)
- ☐ 5. Counting and Integrating readout for direct conversion X-ray Imaging concept, realization and measurements
Kraft, E.; Fischer, P.; Karagounis, M.; Koch, M.; Kruger, H.; Peric, I.; Wermes, N.; Herrmann, C.; Ni M.; Rutten, W.;
[Nuclear Science Symposium Conference Record. 2005 IEEE](#)
Volume 5, 23-29 Oct. 2005 Page(s):2761 - 2765